

Assignment 2, Fall 2014
 Due Wednesday 22 October 2014
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ELEC 4708A: Advanced Digital Integrated Circuits
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Last Name	First Name	ID
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• **Formula**

$$I_{P_{sat}} = 4 \times 10^{-5} \frac{W}{L} (|V_{GS}| - |V_{tp}|)^{1.5}$$

$$I_{N_{sat}} = 1 \times 10^{-4} \frac{W}{L} (V_{GS} - V_{tn})^{1.3}$$

$$I_{sub} = I_0 e^{\frac{V_{GS}-V_t}{nv_T}} \left(1 - e^{\frac{-V_{DS}}{v_T}} \right), I_0 = \beta v_T^2 e^{1.8}, v_T = K \frac{T}{q}$$

$$\beta = \mu C_{ox} \frac{W}{L}, C_{ox} = \frac{\epsilon_{ox}}{t_{ox}}$$

$$S = nv_T \ln 10$$

• **Data**

$$V_{DD} = 1 \text{ V}, V_{tn} = 0.30 \text{ V}, V_{tp} = -0.35 \text{ V}, L_{\min} = 100 \text{ nm}, t_{ox} = 20 \text{ \AA}, n = 1.5$$

$$\mu_n = 80 \frac{\text{cm}^2}{\text{V} \cdot \text{s}}, \mu_p = 30 \frac{\text{cm}^2}{\text{V} \cdot \text{s}}, \epsilon_{ox} = 3.9 \epsilon_0, \epsilon_0 = 8.85 \times 10^{-14} \frac{\text{F}}{\text{cm}}$$

Q1	Q2	Q3	Q4	Q5	Total
/10	/20	/10	/10	/10	/70

[1] Multiple Choice Questions

$5 \times 2 = 10$ marks

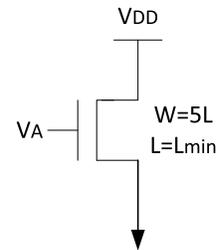
Circle the *most appropriate* answer.

- A) What happens to the superthreshold current (i.e. ON current, or operation current) and subthreshold current (i.e. OFF current, or leakage current) in CMOS circuits as the temperature rises?
- (a) Superthreshold and subthreshold currents both increase.
 - (b) Superthreshold current increases, while subthreshold current decreases.
 - (c) Superthreshold and subthreshold currents both decrease.
 - (d) Superthreshold current decreases, while subthreshold current increases.
- B) The gate tunneling current, as a function of the gate-oxide thickness,
- (a) increases linearly.
 - (b) increases exponentially.
 - (c) decreases linearly.
 - (d) decreases exponentially.
- C) Compare the speed of similarly-sized PMOS and NMOS transistors in a CMOS technology under the same environmental conditions.
- (a) NMOS transistor is about 3 times faster.
 - (b) PMOS transistor is about 2 times faster.
 - (c) They have the same speed.
 - (d) Depends on temperature.
- D) For current CMOS technologies, the main contributor to the static power dissipation is
- (a) Gate tunneling leakage.
 - (b) Subthreshold leakage.
 - (c) Junction leakage.
 - (d) Gate induced drain leakage.
- E) What should be the variations considered for L , V_t , and t_{ox} , respectively, for the fast (F) corner simulations?
- (a) Long, high, thin.
 - (b) Short, low, thin.
 - (c) Long, low, thick.
 - (d) Short, high, thick.

[2] MOSFET capacitance and current

20 marks

Consider the depicted NMOS transistor and calculate the following parameters. Marks will be deducted for results without appropriate units. Assume that the thermal voltage $v_T = 26$ mV at 300 K (i.e. 27 °C, considered room temperature). *Note: make sure you know how to use the formula if it was a PMOS transistor.*



A) C_{ox} in $\text{fF}/\mu\text{m}^2$ and the total gate-oxide capacitance in fF.

2

B) β in A/V^2 .

2

C) I_{ON} , i.e. $V_A = V_{DD}$, in μA .

2

D) I_{OFF} , i.e. $V_A = 0$, at room temperature in nA.

2

E) I_{OFF} , at 75 °C in nA. Assume you do not know the value of q .

2

F) I_d when the transistor is barely ON, i.e. $V_{GS} = V_t$?

2

G) I_d when $V_{GS} = V_{DD}/2$?

2

H) The subthreshold slope? 2

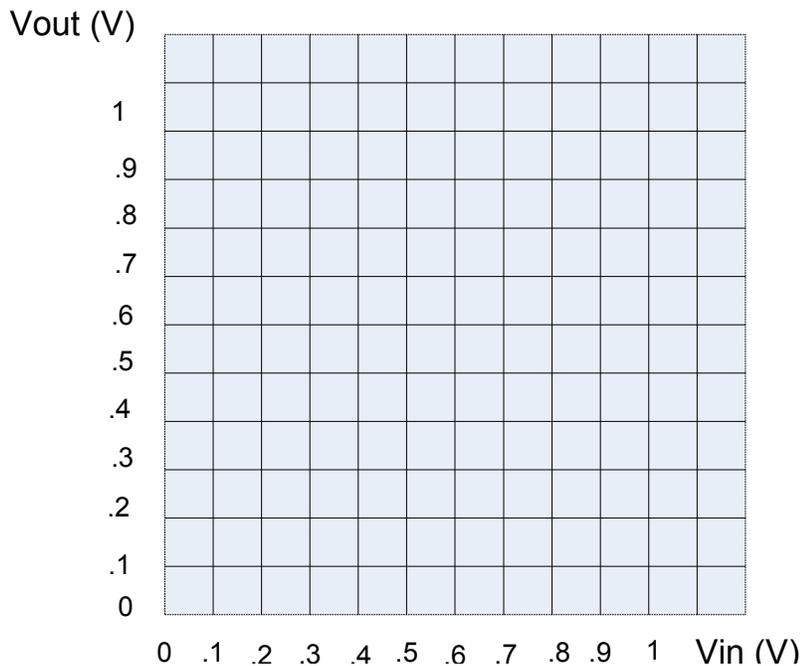
I) Gate potential when the current is 1000 times larger than the OFF current? 2

J) Size (i.e. width) ratio of PMOS to NMOS transistor for equal ON current? 2

[3] VTC

10 marks

A novel inverter has $V_{IL} = 0.3\text{ V}$, $V_{IH} = 0.6\text{ V}$, $V_{OL} = 0.1\text{ V}$, and $V_{OH} = 0.9\text{ V}$. Assume $V_{DD} = 1\text{ V}$.

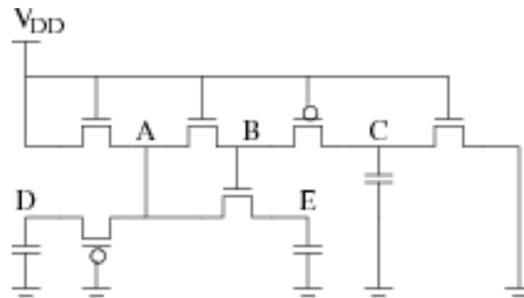


- **3.a)** Plot the VTC (output voltage versus input voltage) of this inverter and obtain values of noise margins high and low: $NM_H = \dots\dots\dots$, and $NM_L = \dots\dots\dots$.
- **3.b)** Plot the VTC of an ideal inverter on the same graph and obtain values of $V_{IL} = \dots\dots\dots\text{V}$, $V_{IH} = \dots\dots\dots\text{V}$, $V_{OL} = \dots\dots\dots\text{V}$, $V_{OH} = \dots\dots\dots\text{V}$, $NM_H = \dots\dots\dots$, and $NM_L = \dots\dots\dots$. No partial marks!

[4] Pass Transistors

10 marks

Obtain the steady-state voltages at the nodes of the following circuit. All capacitances are 0.1 pF each, all transistors have $W/L = 3$, $V_{DD} = 1$ v, $V_{tn} = 0.25$ v, $V_{tp} = -0.35$ v, and $L = 100$ nm. No partial marks!



- $V_A = \dots\dots\dots$, $V_B = \dots\dots\dots$, $V_C = \dots\dots\dots$, $V_D = \dots\dots\dots$, $V_E = \dots\dots\dots$

[5] Leakage

10 marks

Find the subthreshold current for a NAND gate built from unit transistors, i.e. $(W/L)_p = 4$, $(W/L)_n = 2$. Assume inputs $A=B=0$. Show that the subthreshold current through the series transistors is half that of an inverter if $n = 1$.